



Netherlands Institute for  
Catalysis Research

Eindhoven  
January 24-26, 2011

# Course: Characterization in Catalysis Research

Schuit Institute of Catalysis - Eindhoven University of Technology - The Netherlands

NIOK organizes a 3-day course on the characterization of solid catalysts from Monday, January 24 through Wednesday January 26, 2011, at the Eindhoven University of Technology. Although the emphasis of the course will be on the characterization of industrial heterogeneous catalysts by means of spectroscopy, microscopy and diffraction, some attention will also be given to important model systems such as single-crystal surfaces, and particles on planar supports. The course also covers modern *in-situ* techniques to study catalysts during catalytic testing. The course will be taught by a number of experts from The Netherlands. Course director is Dr. Peter Thüne. The number of participants will be limited to about 60.

The fee includes a student version of the course book "Spectroscopy in Catalysis", course material, coffee and tea during breaks and lunches, and amounts to:

- € 225 for participants from academia and Viran members<sup>1</sup>
- € 750 for industrial participants

The timing will be such that most participants from The Netherlands do not need to stay overnight. For participants staying overnight we can recommend hotels at various price levels.

<sup>1</sup> One participant per VIRAN member at reduced price of €225

Registration before December 1<sup>st</sup> by email to Ms Therese-Anne Botman

e-mail: [t.botman@tue.nl](mailto:t.botman@tue.nl)

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Please indicate name, affiliation, address, title, position, phone, and email. You will receive confirmation of registration along with an invoice with payment instructions. Deadline for application: December 1<sup>st</sup> 2010.

#### Subjects covered

- Vibrational spectroscopy (IR, Raman)
- Temperature programmed techniques (TPR, TPO, TDS)
- X-ray photoelectron spectroscopy (XPS)
- X-ray diffraction (XRD)
- Low energy ion scattering (LEIS)
- X-ray absorption spectroscopy (XANES, EXAFS)
- Electron Microscopy (SEM, TEM)
- Rapid screening techniques
- Surface science techniques

#### Speakers include

- Dr. Patricia Kooyman, Delft
- Dr. J.H. Bitter, Utrecht
- Prof.dr. Hidde Brongersma, Eindhoven
- Dr. Jos Keyzer, Geleen
- Prof.dr. Guido Mul, Twente
- Prof.Dr. Hans Niemantsverdriet, Eindhoven
- Dr. Peter Thüne, Eindhoven
- Dr. Kees-Jan Weststrate, Eindhoven

